

STUDY OF THE  $e_0$ -ELECTRON  
YIELD FROM THE SURFACE OF  $^{64}\text{Cu}$   
RADIOACTIVE SOURCES OF VARIOUS  
THICKNESSES AT THEIR POSITRON DECAY

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S u m m a r y

The  $(e\gamma)$ -coincidence method was used to study the yield of  $e_0$ -electrons from the surface of  $^{64}\text{Cu}$  radioactive sources of various thicknesses. The values of 0.120(7), 0.076(4), 0.044(4), 0.034(10), and 0.034(2) for the  $e_0$ -electron yield per a single event of  $\beta^+$ -decay were obtained for the source thicknesses of 1.1, 2.0, 4.8, 11.0, and 14.5  $\mu\text{g}/\text{cm}^2$ , respectively. These values are several times lower than the known  $e_0$ -electron yield at  $\beta^-$ -decay under the same experimental conditions.